

<b>Notice of References Cited</b>	Application/Control No. 10/509,200		Applicant(s)/Patent Under Reexamination SEIDLER ET AL.	
	Examiner Gary F. Paumen		Art Unit 2833	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0164124	08-2004	LUNDSTROM et al.	228/135
*	B	US-5,673,846	10-1997	Gruber, Peter Alfred	228/180.22
*	C	US-5,509,203	04-1996	Yamashita, Chikara	29/879
*	D	US-4,712,721	12-1987	Noel et al.	228/56.3
*	E	US-3,744,129	07-1973	Dewey, Jr., Daniel	29/837
*	F	US-2002/0029905	03-2002	Okada et al.	174/263
*	G	US-7,043,830	05-2006	Farnworth, Warren M.	29/842
*	H	US-6,534,726	03-2003	Okada et al.	174/263
*	I	US-6,452,112	09-2002	Terashima et al.	174/260
*	J	US-6,294,745	09-2001	Gruber, Peter Alfred	174/263
*	K	US-5,471,368	11-1995	Downie et al.	361/760
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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